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| Notice of References Cited | Application/Control No. 10/568,280 | | Applicant(s)/Patent Under Reexamination TANIGUCHI ET AL. | |
| | Examiner FAN NG | | Art Unit 4145 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|----------------------|----------------|
| * | A | US-6,961,364 | 11-2005 | Laroia et al. | 375/132 |
| * | B | US-5,889,438 | 03-1999 | Yamaguchi, Shigenori | 331/17 |
| * | C | US-6,327,481 | 12-2001 | Nagashima, Noriaki | 455/562.1 |
| * | D | US-6,240,368 | 05-2001 | Kreft, Peter | 701/214 |
| * | E | US-6,359,585 | 03-2002 | Bechman et al. | 342/359 |
| * | F | US-6,546,026 | 04-2003 | Goeddel, Thomas W. | 370/513 |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

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